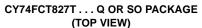
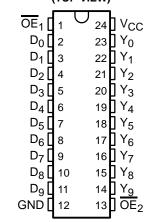
- **Function, Pinout, and Drive Compatible** With FCT, F, and AM29827 Logic
- Reduced V_{OH} (Typically = 3.3 V) Versions of Equivalent FCT Functions
- **Edge-Rate Control Circuitry for** Significantly Improved Noise Characteristics
- Ioff Supports Partial-Power-Down Mode Operation
- **ESD Protection Exceeds JESD 22**
 - 2000-V Human-Body Model (A114-A)
 - 200-V Machine Model (A115-A)
 - 1000-V Charged-Device Model (C101)
- **3-State Outputs**
- **Matched Rise and Fall Times**
- **Fully Compatible With TTL Input and Output Logic Levels**
- CY54FCT827T
 - 32-mA Output Sink Current
 - 12-mA Output Source Current
- CY74FCT827T
 - 64-mA Output Sink Current
 - 32-mA Output Source Current

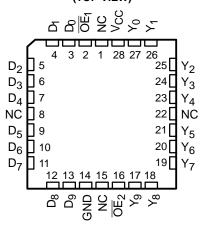
description

The 'FCT827T devices are 10-bit bus drivers that provide high-performance bus-interface buffering for wide data/address paths or buses carrying parity. The 10-bit buffers have NANDed output enables for maximum control flexibility. The 'FCT827T devices are designed high-capacitance-load drive capability, while providing low-capacitance bus loading at both inputs and outputs. All outputs are designed for low-capacitance bus loading high-impedance state.





CY74FCT827T . . . L PACKAGE (TOP VIEW)



NC - No internal connection

This device is fully specified for partial-power-down applications using I_{off} . The I_{off} circuitry disables the outputs, preventing damaging current backflow through the device when it is powered down.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



ORDERING INFORMATION

TA	PAC	(AGE†	SPEED (ns)	ORDERABLE PART NUMBER	TOP-SIDE MARKING
	QSOP – Q	QSOP – Q Tape and reel 4.4 CY74FCT827CTQC		CY74FCT827CTQCT	FCT827C
	SOIC - SO	Tube	4.4	CY74FCT827CTSOC	FCT827C
-40°C to 85°C	3010 - 30	Tape and reel	4.4	CY74FCT827CTSOCT	FC1627C
-40 C to 65 C	QSOP – Q	Tape and reel	8	CY74FCT827ATQCT	FCT827A
	SOIC - SO	Tube	8	CY74FCT827ATSOC	FCT827A
	3010 - 30	Tape and reel	8	CY74FCT827ATSOCT	FC1627A
−55°C to 125°C	LCC - L Tube		9	CY54FCT827ATLMB	

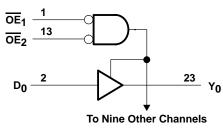
[†] Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.

FUNCTION TABLE

	INPUTS		OUTPUT	FUNCTION
OE ₁	OE ₂	D	Υ	FUNCTION
L	L	L	L	Transparent
L	L	Н	Н	Transparent
Н	Х	Χ	Z	2 atata
Х	Н	Χ	Z	3-state

H = High logic level, L = Low logic level, X = Don't care, Z = High-impedance state

logic diagram (positive logic)



Pin numbers shown are for the Q and SO packages.

absolute maximum rating over operating free-air temperature range (unless otherwise noted)‡

Supply voltage range to ground potential	\dots –0.5 V to 7 V
DC input voltage range	\dots –0.5 V to 7 V
DC output voltage range	\dots –0.5 V to 7 V
DC output current (maximum sink current/pin)	120 mA
Package thermal impedance, θ _{JA} (see Note 1): Q package	61°C/W
SO package	46°C/W
Ambient temperature range with power applied, T _A	. -65°C to 135°C
Storage temperature range, T _{stq}	. -65°C to 150°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The package thermal impedance is calculated in accordance with JESD 51-7.



recommended operating conditions (see Note 2)

		CY!	54FCT82	7T	CY7	UNIT		
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
VCC	Supply voltage	4.5	5	5.5	4.75	5	5.25	V
VIH	High-level input voltage	2			2			V
VIL	Low-level input voltage			0.8			0.8	V
ІОН	High-level output current			-12			-32	mA
l _{OL}	Low-level output current			32			64	mA
T _A	Operating free-air temperature	-55		125	-40	•	85	°C

NOTE 2: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETED		TEST COMPLETION	ue.	CY	54FCT82	27T	CY	74FCT82	?7T	UNIT
PARAMETER		TEST CONDITION	V5	MIN	TYP†	MAX	MIN	TYP [†]	MAX	UNII
V	V _{CC} = 4.5 V,	I _{IN} = -18 mA			-0.7	-1.2				V
VIK	$V_{CC} = 4.75 \text{ V},$	$I_{IN} = -18 \text{ mA}$						-0.7	-1.2	V
	$V_{CC} = 4.5 \text{ V},$	$I_{OH} = -12 \text{ mA}$		2.4	3.3					
Voн	V _{CC} = 4.75 V	$I_{OH} = -32 \text{ mA}$					2			V
	VCC = 4.75 V	$I_{OH} = -15 \text{ mA}$					2.4	3.3		
Voi	$V_{CC} = 4.5 \text{ V},$	$I_{OL} = 32 \text{ mA}$			0.3	0.55				٧
VOL	$V_{CC} = 4.75 \text{ V},$	$I_{OL} = 64 \text{ mA}$						0.3	0.55	V
V_{hys}	All inputs				0.2			0.2		V
	$V_{CC} = 5.5 \text{ V},$	VIN = VCC				5				μА
lj .	$V_{CC} = 5.25 \text{ V},$	VIN = VCC							5	μΑ
l	$V_{CC} = 5.5 \text{ V},$	$V_{IN} = 2.7 \text{ V}$				±1				μА
lН	$V_{CC} = 5.25 \text{ V},$	$V_{1N} = 2.7 \text{ V}$							±1	μΑ
Ι _{ΙL}	$V_{CC} = 5.5 \text{ V},$	V _{IN} = 0.5 V				±1				μΑ
ЧL	$V_{CC} = 5.25 \text{ V},$	$V_{IN} = 0.5 V$							±1	μΑ
lozh	$V_{CC} = 5.5 \text{ V},$	$V_{OUT} = 2.7 V$				10				μΑ
¹ OZH	$V_{CC} = 5.25 \text{ V},$	$V_{OUT} = 2.7 V$							10	μΑ
lozi	$V_{CC} = 5.5 \text{ V},$	$V_{OUT} = 0.5 V$				-10				μΑ
IOZL	$V_{CC} = 5.25 \text{ V},$	$V_{OUT} = 0.5 V$							-10	μΑ
los‡	$V_{CC} = 5.5 \text{ V},$	$V_{OUT} = 0 V$		-60	-120	-225				mA
108+		V _{OUT} = 0 V					-60	-120	-225	ША
l _{off}	$V_{CC} = 0 V$,	V _{OUT} = 4.5 V				±1			±1	μΑ
loc	$V_{CC} = 5.5 \text{ V},$	$V_{IN} \leq 0.2 V$	$V_{IN} \ge V_{CC} - 0.2 \text{ V}$		0.1	0.2				mA
Icc	$V_{CC} = 5.25 \text{ V},$	$V_{IN} \leq 0.2 V$	$V_{IN} \ge V_{CC} - 0.2 V$					0.1	0.2	ША
ΔlCC		= 3.4 V§, f ₁ = 0, Out			0.5	2				mA
∆i((t	$V_{CC} = 5.25 \text{ V}, V_{IN}$	= 3.4 V§, f ₁ = 0, Ou	itputs open					0.5	2	ША

[†] Typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.



Not more than one output should be shorted at a time. Duration of short should not exceed one second. The use of high-speed test apparatus and/or sample-and-hold techniques are preferable to minimize internal chip heating and more accurately reflect operational values. Otherwise, prolonged shorting of a high output can raise the chip temperature well above normal and cause invalid readings in other parametric tests. In any sequence of parameter tests, Ios tests should be performed last.

[§] Per TTL-driven input (V_{IN} = 3.4 V); all other inputs at V_{CC} or GND

CY54FCT827T, CY74FCT827T 10-BIT BUFFERS WITH 3-STATE OUTPUTS

SCCS034A - SEPTEMBER 1994 - REVISED OCTOBER 2001

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted) (continued)

DADAMETER		TEST CONDITIONS		CY	54FCT82	27T	CY	74FCT82	:7T	
PARAMETER		MIN	TYP [†]	MAX	MIN	TYP [†]	MAX	UNIT		
ioon¶	V_{CC} = 5.5 V, One inports open, \overline{OE}_1 over $V_{IN} \le 0.2$ V or $V_{IN} \ge 0.2$	or $\overline{OE}_2 = GND$,		0.06	0.12				mA/	
ICCD¶	V_{CC} = 5.25 V, One in Outputs open, \overline{OE}_1 over $V_{IN} \le 0.2$ V or $V_{IN} \ge 0.2$	or $\overline{OE}_2 = GND$,	% duty cycle,					0.06	0.12	MHz
		One bit switching at f ₁ = 10 MHz	$V_{IN} \le 0.2 \text{ V or}$ $V_{IN} \ge V_{CC} - 0.2 \text{ V}$		0.7	1.4				
	V _{CC} = 5.5 V, Outputs open,	at 50% duty cycle	$V_{IN} = 3.4 \text{ V or GND}$		1	2.4				
	OE_1 or $OE_2 = GND$	10 bits switching at f ₁ = 2.5 MHz	$V_{IN} \le 0.2 \text{ V or}$ $V_{IN} \ge V_{CC} - 0.2 \text{ V}$		1.6	3.2				
lc#		at 50% duty cycle	V _{IN} = 3.4 V or GND		4.1	13.2				mA
I IC		One bit switching at f ₁ = 10 MHz	$V_{IN} \le 0.2 \text{ V or}$ $V_{IN} \ge V_{CC} - 0.2 \text{ V}$					0.7	1.4	IIIA
	V _{CC} = 5.25 V,	at 50% duty cycle	V _{IN} = 3.4 V or GND					1	2.4	
	Outputs open, OE ₁ or OE ₂ = GND					1.6	3.2			
		at 50% duty cycle	V _{IN} = 3.4 V or GND					4.1	13.2	
C _i			_		5	10		5	10	pF
Co					9	12		9	12	pF

This parameter is derived for use in total power-supply calculations.

 $^{\#}$ IC = ICC + \triangle ICC × D_H × N_T + ICCD (f₀/2 + f₁ × N₁)

Where:

I_C = Total supply current

ICC = Power-supply current with CMOS input levels

 ΔI_{CC} = Power-supply current for a TTL high input (V_{IN} = 3.4 V)

D_H = Duty cycle for TTL inputs high N_T = Number of TTL inputs at D_H

I_{CCD} = Dynamic current caused by an input transition pair (HLH or LHL)

f₀ = Clock frequency for registered devices, otherwise zero

f₁ = Input signal frequency

N₁ = Number of inputs changing at f₁

All currents are in milliamperes and all frequencies are in megahertz.

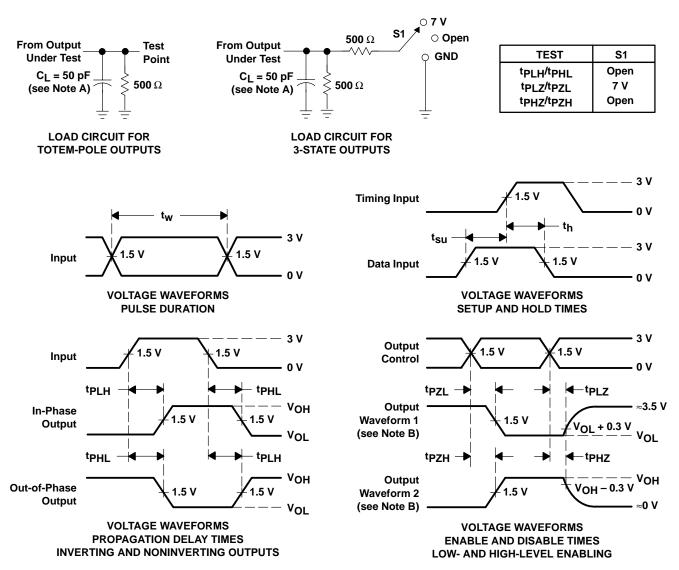
|| Values for these conditions are examples of the I_{CC} formula.



switching characteristics over operating free-air temperature range (see Figure 1)

PARAMETER	FROM	то	TEST LOAD	CY54FC1	827AT	CY74FCT	827AT	CY74FCT	827CT	UNIT
PARAMETER	(INPUT)	(OUTPUT)	TEST LOAD	MIN	MAX	MIN	MAX	MIN	MAX	UNII
t _{PLH}	D	Υ	$C_L = 50 \text{ pF},$	1.5	9	1.5	8	1.5	4.4	ns
t _{PHL}	ט	ī	$R_L = 500 \Omega$	1.5	9	1.5	8	1.5	4.4	115
^t PLH	D	Υ	C _L = 300 pF,	1.5	17	1.5	15	1.5	10	ns
t _{PHL}	ט	ī	$R_L = 500 \Omega$	1.5	17	1.5	15	1.5	10	115
^t PZH	ŌE	Y	C _L = 50 pF,	1.5	13	1.5	12	1.5	7	ns
tPZL	OL .	ī	$R_L = 500 \Omega$	1.5	13	1.5	12	1.5	7	110
^t PZH	ŌE	Y	C _L = 300 pF,	1.5	25	1.5	23	1.5	14	ns
t _{PZL}	OE	ı	$R_L = 500 \Omega$	1.5	25	1.5	23	1.5	14	10
t _{PHZ}	ŌE	Υ	C _L = 5 pF,	1.5	9	1.5	9	1.5	5.7	20
t _{PHL}	SE	ī	$R_L = 500 \Omega$	1.5	9	1.5	9	1.5	5.7	ns
t _{PHZ}	ŌĒ	Υ	$C_L = 50 \text{ pF},$	1.5	10	1.5	10	1.5	6	200
t _{PHL}	OE .	r	$R_L = 500 \Omega$	1.5	10	1.5	10	1.5	6	ns

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_I includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms







9-Mar-2021

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
5962-9224701M3A	ACTIVE	LCCC	FK	28	1	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	5962- 9224701M3A	Samples
CY74FCT827ATQCT	ACTIVE	SSOP	DBQ	24	2500	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	FCT827A	Samples
CY74FCT827ATSOC	ACTIVE	SOIC	DW	24	25	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	FCT827A	Samples
CY74FCT827ATSOCT	ACTIVE	SOIC	DW	24	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	FCT827A	Samples
CY74FCT827CTQCT	ACTIVE	SSOP	DBQ	24	2500	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	FCT827C	Samples
CY74FCT827CTQCTG4	ACTIVE	SSOP	DBQ	24	2500	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	FCT827C	Samples
CY74FCT827CTSOC	ACTIVE	SOIC	DW	24	25	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	FCT827C	Samples
CY74FCT827CTSOCT	ACTIVE	SOIC	DW	24	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	FCT827C	Samples

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

⁽³⁾ MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

⁽⁴⁾ There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

⁽⁵⁾ Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.



PACKAGE OPTION ADDENDUM

9-Mar-2021

(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





Α0	Dimension designed to accommodate the component width
	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

All ulmensions are nominal												
Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CY74FCT827ATQCT	SSOP	DBQ	24	2500	330.0	16.4	6.5	9.0	2.1	8.0	16.0	Q1
CY74FCT827ATSOCT	SOIC	DW	24	2000	330.0	24.4	10.75	15.7	2.7	12.0	24.0	Q1
CY74FCT827CTQCT	SSOP	DBQ	24	2500	330.0	16.4	6.5	9.0	2.1	8.0	16.0	Q1
CY74FCT827CTSOCT	SOIC	DW	24	2000	330.0	24.4	10.75	15.7	2.7	12.0	24.0	Q1

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*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CY74FCT827ATQCT	SSOP	DBQ	24	2500	853.0	449.0	35.0
CY74FCT827ATSOCT	SOIC	DW	24	2000	350.0	350.0	43.0
CY74FCT827CTQCT	SSOP	DBQ	24	2500	853.0	449.0	35.0
CY74FCT827CTSOCT	SOIC	DW	24	2000	350.0	350.0	43.0

PACKAGE MATERIALS INFORMATION

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TUBE



*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
CY74FCT827ATSOC	DW	SOIC	24	25	506.98	12.7	4826	6.6
CY74FCT827CTSOC	DW	SOIC	24	25	506.98	12.7	4826	6.6

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